

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination TRAN ET AL.	
		Examiner VAN H NGUYEN	Art Unit 2126	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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**NON-PATENT DOCUMENTS**

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